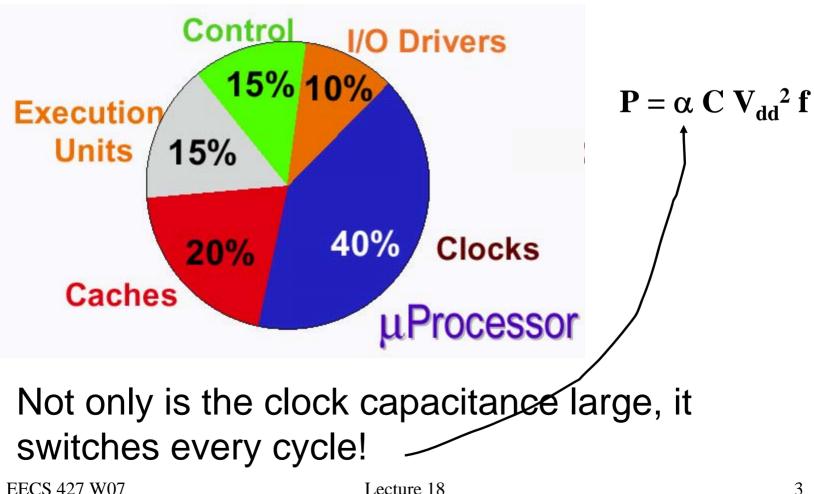
EECS 427 Lecture 18: Clocking, Timing/Latch Design Reading: 10.3.1, 10.3.2, 7.4.1

Lecture Overview

- Last time: Timing and FlipFlop design
 Setup-hold time, D-Q delay
- Today
 - Clock distribution
 - Impact of clock uncerainty
 - Noise sources relevant to FFs
 - Pulsed registers

Clocks: Power-Hungry



Clocks – Objective

- Ensure that timing elements see the clock signal with zero relative phase difference.
- Clock signal seen at all timing-elements must have exactly the same frequency.(Which is why almost ALL clock distribution methods simply distribute one signal all over the chip)
- Control dissipation in the clock network, which toggles 2 times per cycle.
- Minimize area overhead of such a clock system.

Clock Distribution Metric: Area

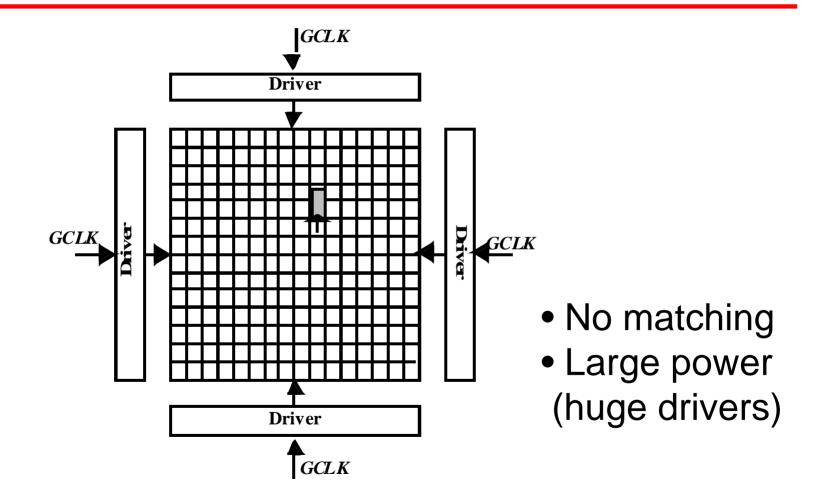
- Clock networks consume silicon area (clock drivers, PLL, etc.) and routing area
- Routing area is most vital
- Top-level metals are used to reduce RC delays
 - These levels are precious resources (unscaled)
 - Power routing, clock routing, key global signals
- By minimizing area used, we also reduce wiring capacitance & power
- Typical #'s: Intel Itanium 4% of M4/5 used in clock routing

Slew Rates

- To maintain signal integrity and latch performance, minimum slew rates are required
- Too slow clock is more susceptible to noise, process-variation, latches are slowed down, eats into timing budget
- Too fast burning too much power, overdesigned network, enhanced ground bounce
- Rule-of-thumb: T_{rise} and T_{fall} of clock are each between 10-20% of clock period (10% - aggressive target)

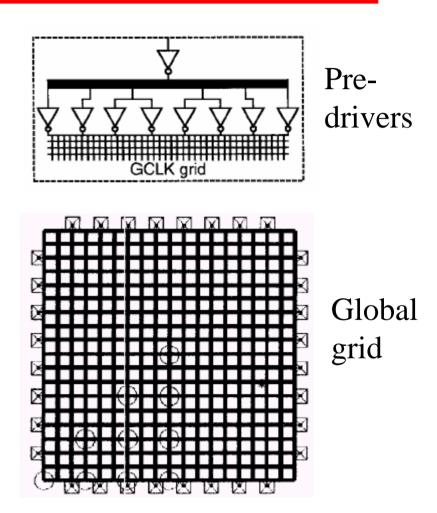
- 1 GHz clock; $T_{rise} = T_{fall} = 100-200 ps$

The Grid System



Network Types: Grid

- Gridded clock distribution was common on earlier DEC Alpha microprocessors
- Advantages:
 - Skew determined by grid density and not overly sensitive to load position
 - Clock signals are available everywhere
 - Tolerant to process variations
 - Usually yields extremely low skew values



EECS 427 W07

Lecture 18

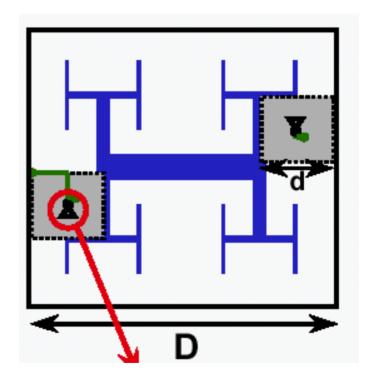
Grid Disadvantages

- Huge amounts of wiring & power
 - Wire cap large
 - Strong drivers needed pre-driver cap large
 - Routing area large
- To minimize all these penalties, make grid pitch coarser
 - Skew gets worse
 - Losing the main advantage
- Don't overdesign let the skew be as large as tolerable
- Grids aren't feasible for most designs due to power

Network Types: Tree

Original H-tree (Bakoglu)

- One large central driver
- Recursive H-style structure to match wirelengths
- Halve wire width at branching points to reduce reflections

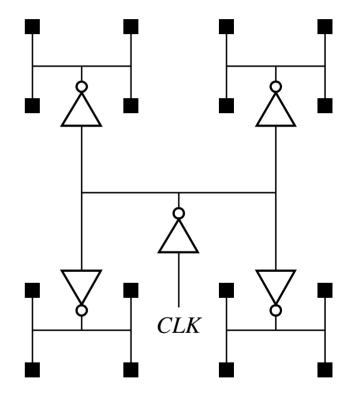


H-Tree Problems

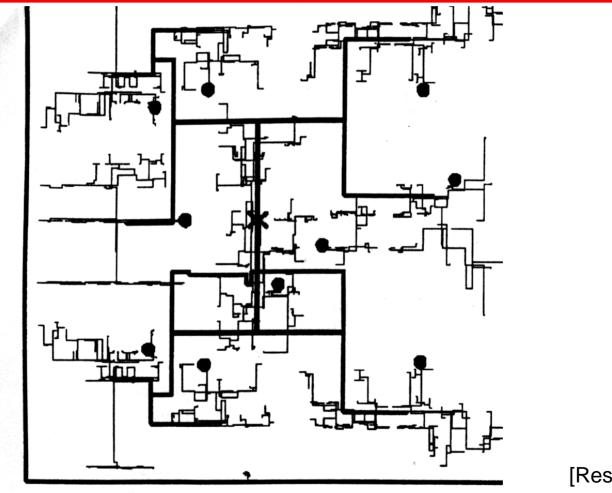
- Drawback to original tree concept
 - slew degradation along long RC paths
 - unrealistically large central driver
 - Clock drivers can create large temperature gradients (ex. Alpha 21064 ~30° C)
 - non-uniform load distribution
- Inherently non-scalable (wire resistance skyrockets)
- Solution to some problems
 - Introduce intermediate buffers along the way
 - Specifically at branching points

Buffered H-tree

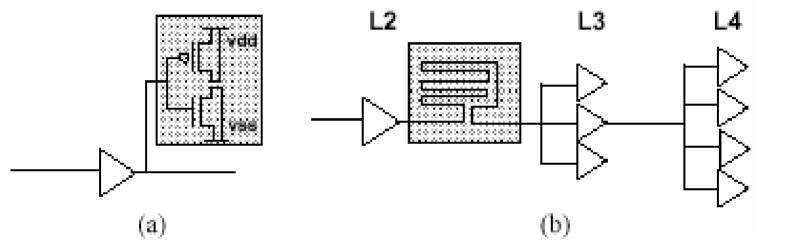
- Advantages
 - Ideally zero-skew
 - Can be low power (depending on skew requirements)
 - Low area (silicon and wiring)
 - CAD tool friendly (regular)
- Disadvantages
 - Sensitive to process variations
 - Local clocking loads are inherently non-uniform



Realistic H-tree



Balancing a Tree



Some techniques:

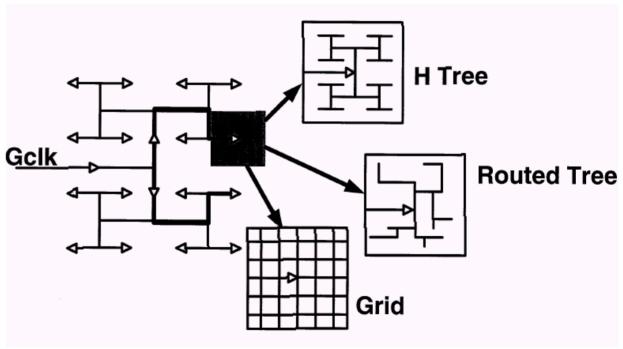
Con: Routing area often more valuable than silicon

- a) Introduce dummy loads
- b) Snaking of wirelength to match delays

EECS 427 W07

Network of choice in highperformance

- Globally Tree
- Why?
- Power requirements are reduced compared to global grid
 - Smaller routing requirements, frees up global tracks
- Trees are easily balanced at the global level
 - Keeps global skew low (with minimal process variation)



Clock Waveform Nonidealities

Clock skew

– Spatial variation in temporally equivalent clock edges, δ

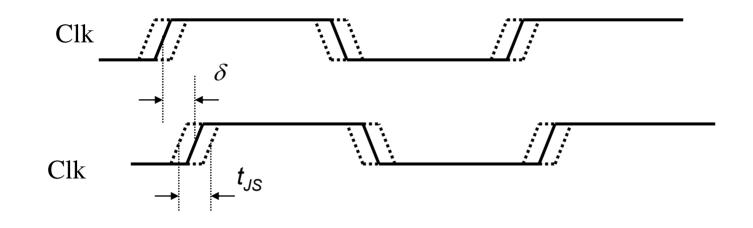
Clock jitter

- Temporal variations in consecutive edges of the clock signal
 - Cycle-to-cycle (short-term) t_{JS}
 - Long term t_{JL}

• Variation of the pulse width (duty cycle)

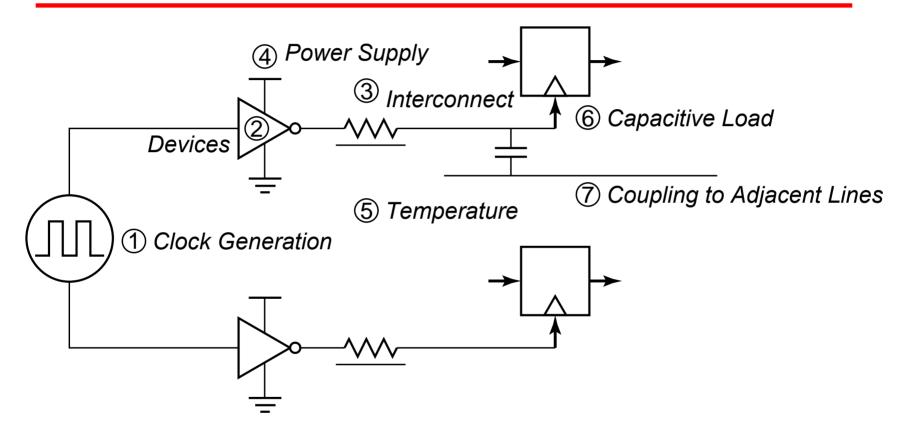
- Important for level sensitive (latch-based) clocking

Clock Skew and Jitter



- Both skew and jitter impact the effective cycle time
- Skew can be useful. Setup time Hold time tradeoff
- Jitter always degrades performance

Clock Uncertainties

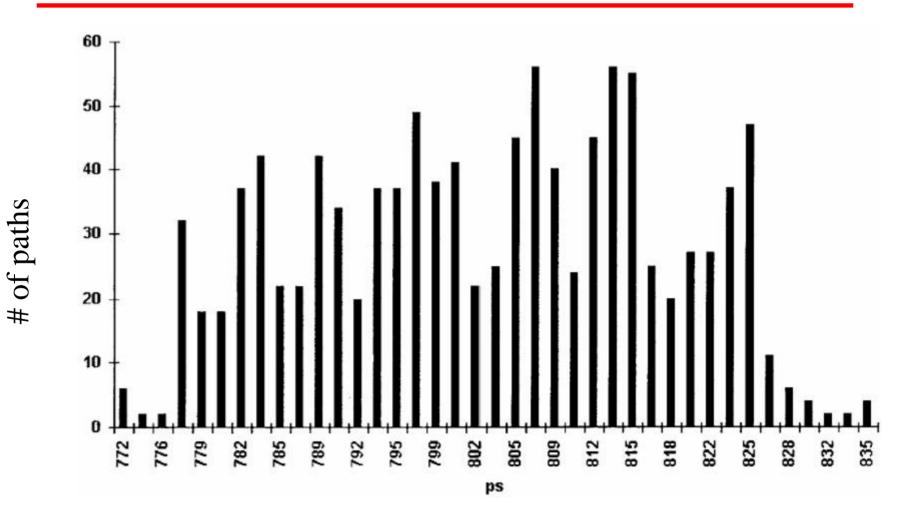


Sources of clock uncertainty

Jitter Sources

- Caused by variations in clock period that result from:
 - Ring oscillator clocks can be quite "jittery".
 - Phased-lock loop (PLL) oscillation frequency
 - Various noise sources affecting clock generation and distribution
 - Ex. Power supply noise which dynamically alters the drive strength of intermediate buffer stages. (A "derivative effect"??)
 - What happens with a ring oscillator clock?

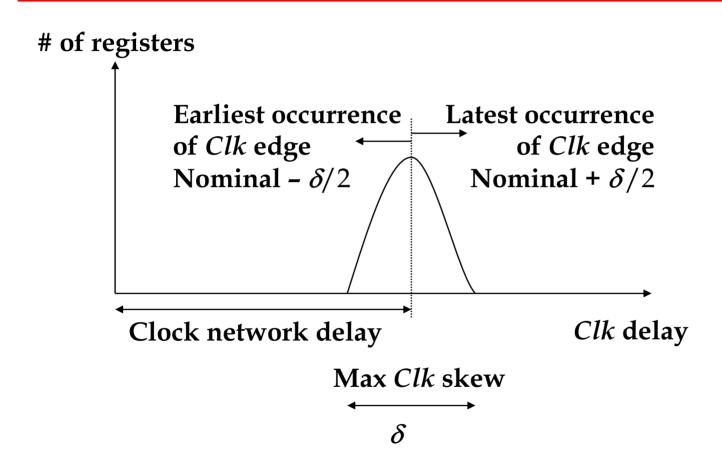
IBM microprocessor clock skew



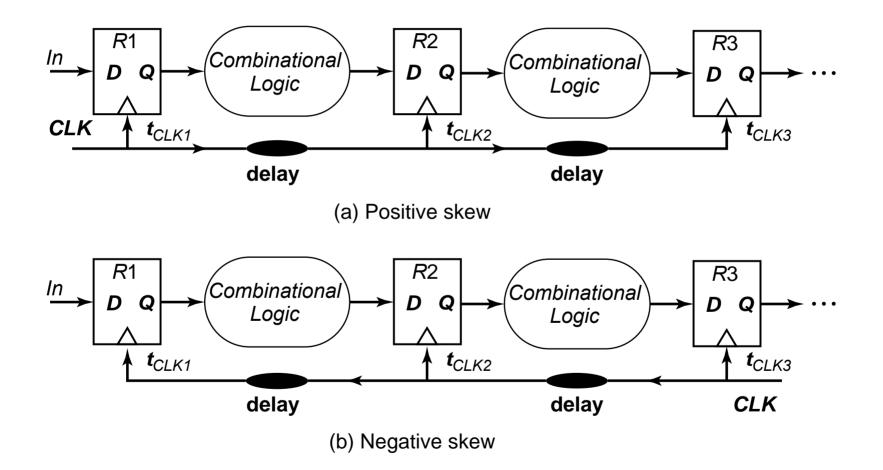
EECS 427 W07

Lecture 18

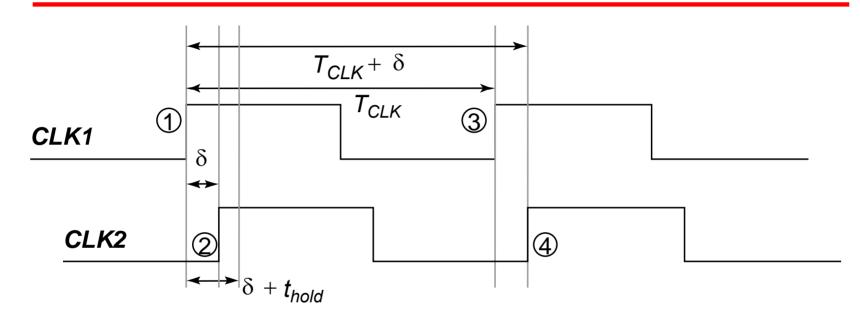
Idealized View of Clock Skew



Positive and Negative Skew

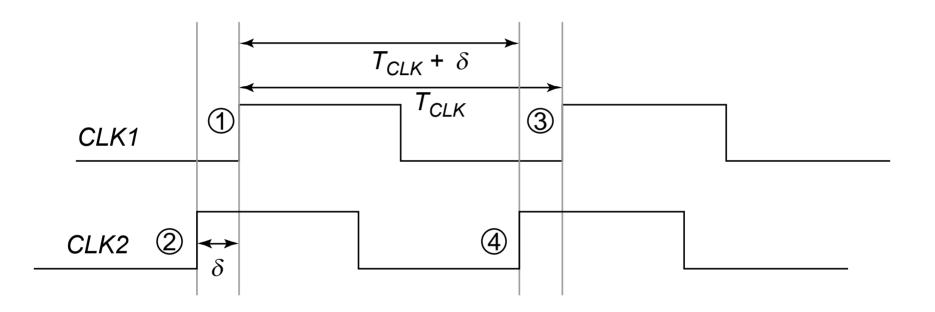


Positive Skew, $\delta > 0$



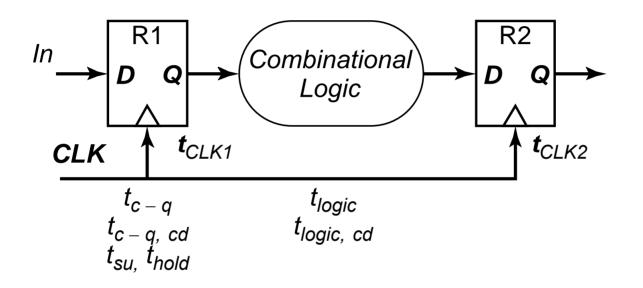
Launching edge arrives before the receiving edge Good for performance, bad for hold time Key: Hold time violations cannot be fixed by running the clock slower! Question: Will it help if I scale the voltage?? EECS 427 W07

Negative Skew, $\delta < 0$



Receiving edge arrives before the launching edge Bad for performance, good for hold time violations

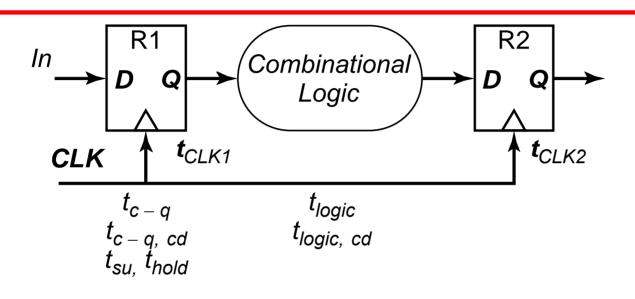
Timing Constraints



Minimum cycle time: $T \ge t_{c-q} + t_{su} + t_{logic} - \delta$

Worst case is when receiving edge arrives early (negative δ)

Timing Constraints



Hold time constraint:

$$t_{(c-q, cd)} + t_{(logic, cd)} > t_{hold} + \delta$$

Worst case is when receiving edge arrives late (positive skew) Race between data and clock

cd: contamination delay (fastest possible delay)

EECS 427 W07

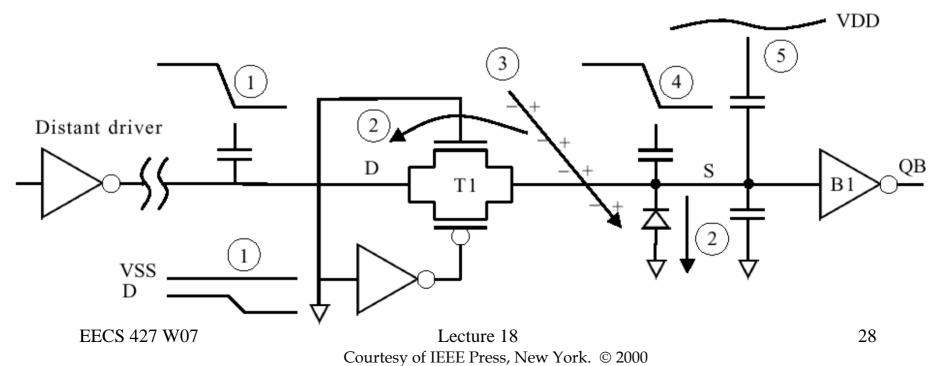
Lecture 18

Requirements in Flip-Flop Design

- High speed:
 - Small Clk-Output delay
 - Small setup time
 - Small hold time→Inherent race immunity
- Low power
- Small clock load (clock power is very large)
- High driving capability
- Integration of the logic into flip-flop
- Multiplexed or clock scan (testability)
- Robustness
- Crosstalk insensitivity
 - Dynamic/high impedance nodes are affected

Sources of Noise

- (1) Noise on input
- 2 Leakage
- (3) α -Particle and cosmic rays
- (4) Unrelated signal coupling
- 5 Power supply ripple



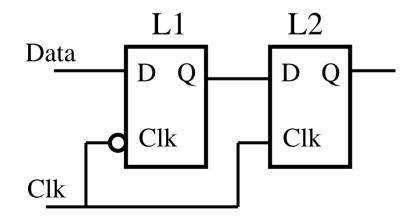
Flip-Flop Robustness

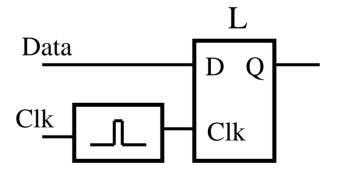
- Input isolation
 - Don't use a pass-transistor directly at the input (use a buffer)
- Storage node related issues:
- Robustness
 - No floating nodes, create pseudo-static storage nodes
- Min capacitance limit
 - Storage node (middle of cross-couple) should have a decent amount of capacitance for noise immunity
 - Too much will slow things down though...
- Preventing exposure
 - Wires associated with storage node should be short, suppress possible coupling to other nodes

Pulse-Triggered Registers An Alternative Approach

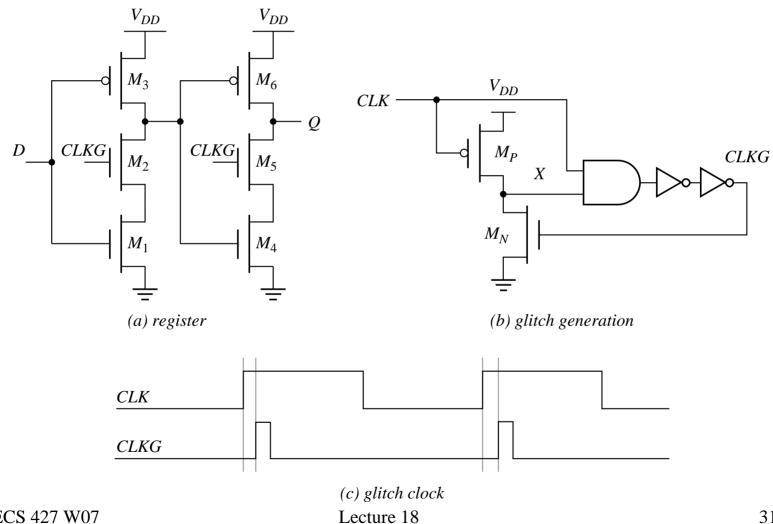
Ways to design an edge-triggered sequential cell:

Master-Slave Latches Pulse-Triggered Latch



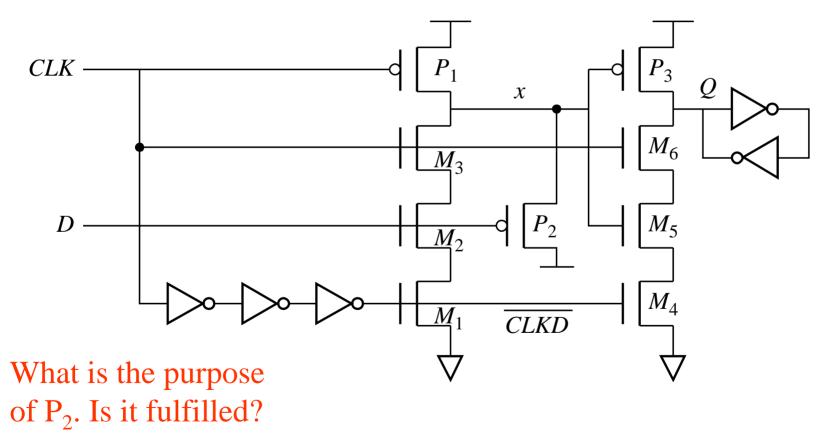


Pulsed Register



Another Pulsed Register Topology

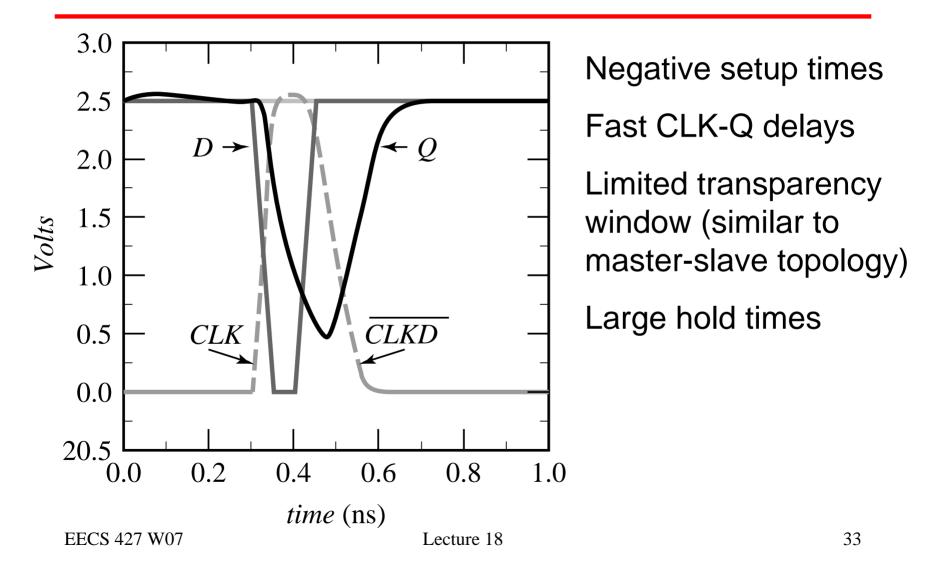
Hybrid Latch – Flip-flop (HLFF), AMD K-6 and K-7:



EECS 427 W07

Lecture 18

Pulsed Register Timing Diagram



Summary

- Clocks strongly impact IC performance (timing) and are not ideal
 - Skew and jitter are commonly discussed non-idealities
 - Skew is typically larger and more heavily focused on
 - More on skew later in class when we discuss clock distribution techniques
- Rough rule of thumb: skew should be kept < 10% of clock period
- Sequential elements eat up a significant amount of total timing budget + power resources
 - They are therefore extremely important to design carefully
 - Robustness is critical as well
- D-Q delay is best overall performance measure for edge-triggered registers since it effectively combines both setup and CLK-Q delays
- New designs like pulsed registers provide enhanced performance with some added design complexity